

# Precision Laser Assisted Photoelectrochemical Fabrication of III-V Semiconductor Quantum Structures

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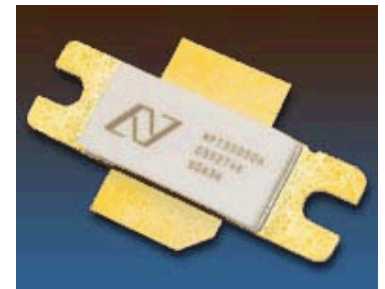
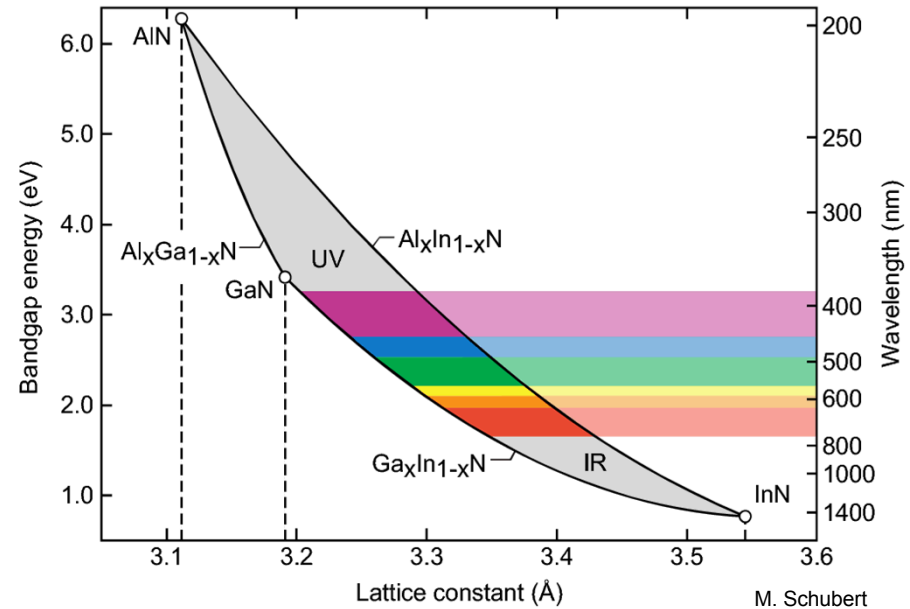
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# About Solid State Lighting (SSL)

## *Basis: III-Nitride (Al, Ga, In, N) Semiconductors*

### III-Nitride (AlGaInN) Properties

- **Direct RT bandgaps: ~0.7-6.2 eV**
- Solid alloy system (tunable bandgaps)
- High breakdown field, mobility, thermal conductivity, melting temperature
- Radiation resistant and chemically inert
- InGaN covers entire visible & bulk of solar spectrum (PV material?)
- *Used in LEDs, blue laser diodes, high power transistors, HEMTs*



Nitronex GaN power transistor

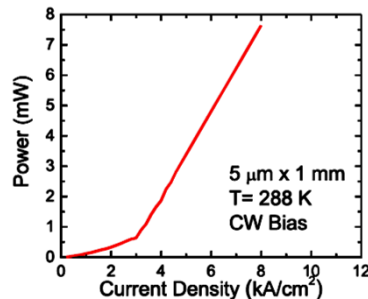
# InGaN Quantum Dot (QD) Emitters

- **Long wavelength visible emitters:**
  - Nanostructure (NWs, QDs) can incorporate more indium
  - High efficiency yellow, orange, and red emission
  - RGB and RYGB emitters require high efficiency yellow to red emitters
- **Visible QD diode lasers:**
  - Laser for lighting is gaining momentum
  - Low threshold, high efficiency, better temperature performance
  - Monodisperse QDs

## InGaN QD laser:

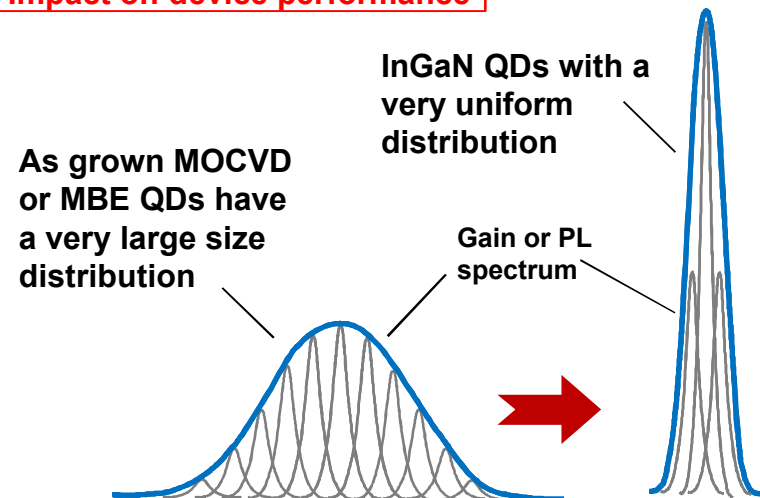
- **University of Michigan**
- **Electrically injected**
- **630 nm**
- **$T_o = 236\text{K}$**

Frost et al., IEEE JQE,  
49, 923 (2013).



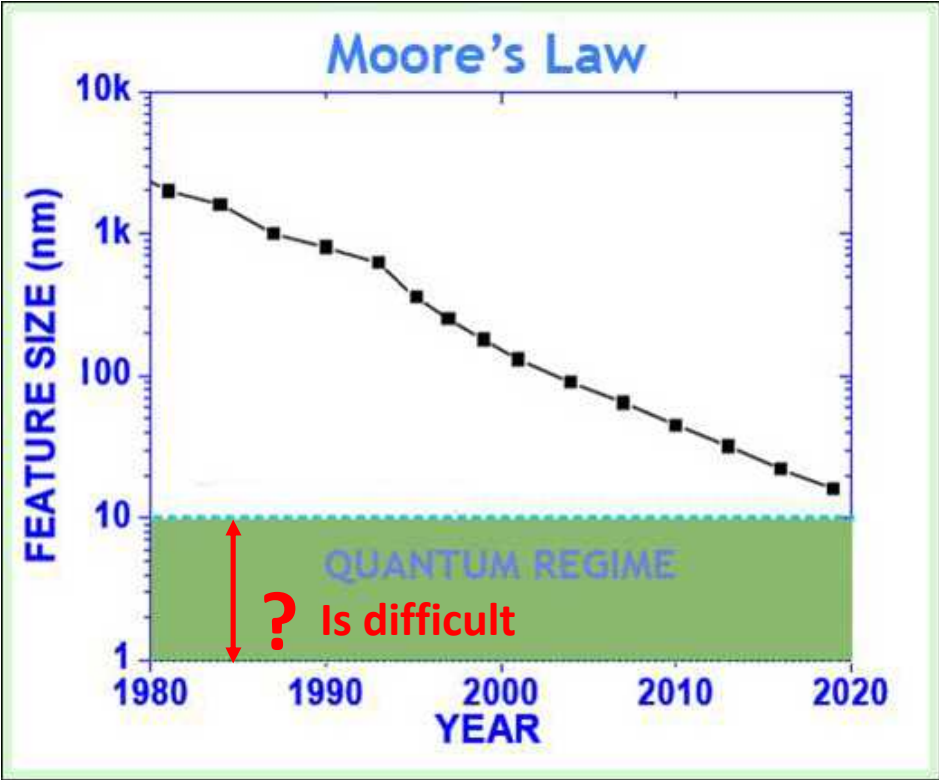
## Monodisperse QD Distributions

### Impact on device performance



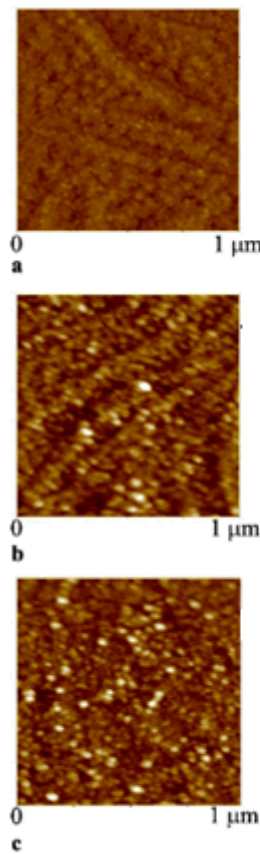
# Quantum confined structures: fabrication

## 1. Lithographical methods



## 2. S-K quantum dots

Strain-induced Stranski–Krastanov growth



Random location  
Broad size distribution

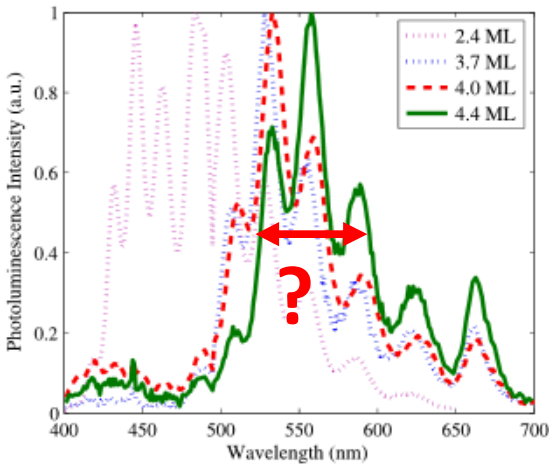
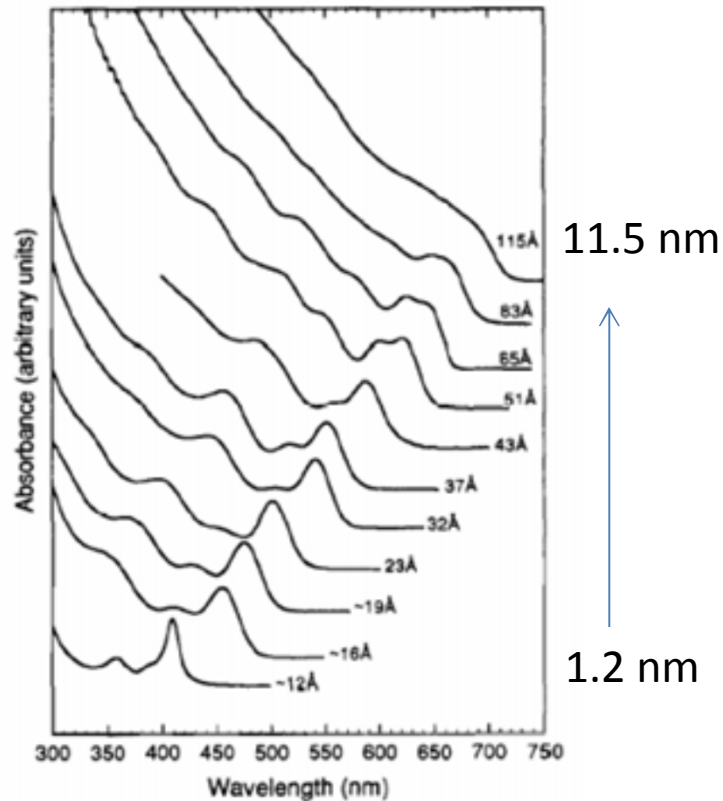


Fig. 5 Normalized photoluminescence intensity versus wavelength at room temperature for 2.4-, 3.7-, 4.0-, and 4.4-ML-thick InGaN

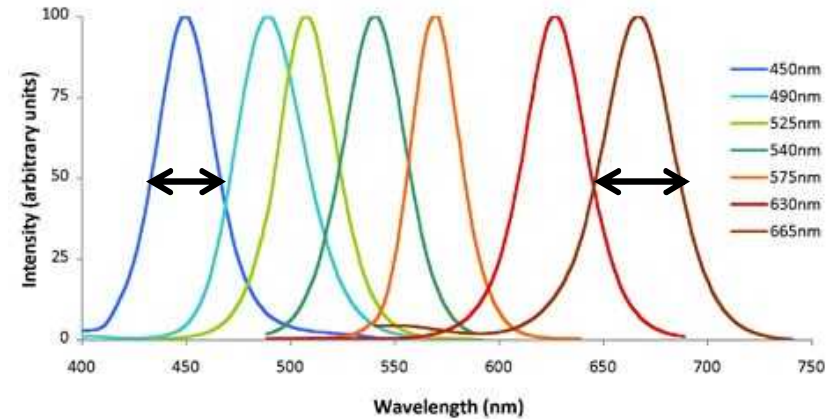
Fig. 2 AFM ( $1\ \mu\text{m} \times 1\ \mu\text{m}$ ) images of a 2.9 ML, b 4.4 ML, and c 5.8 ML InGaN grown at  $T = 633^{\circ}\text{C}$

# Quantum confined structures: fabrication

## 3. Colloidal chemistries: simple and size-tunable



CdSe NPs in hexane



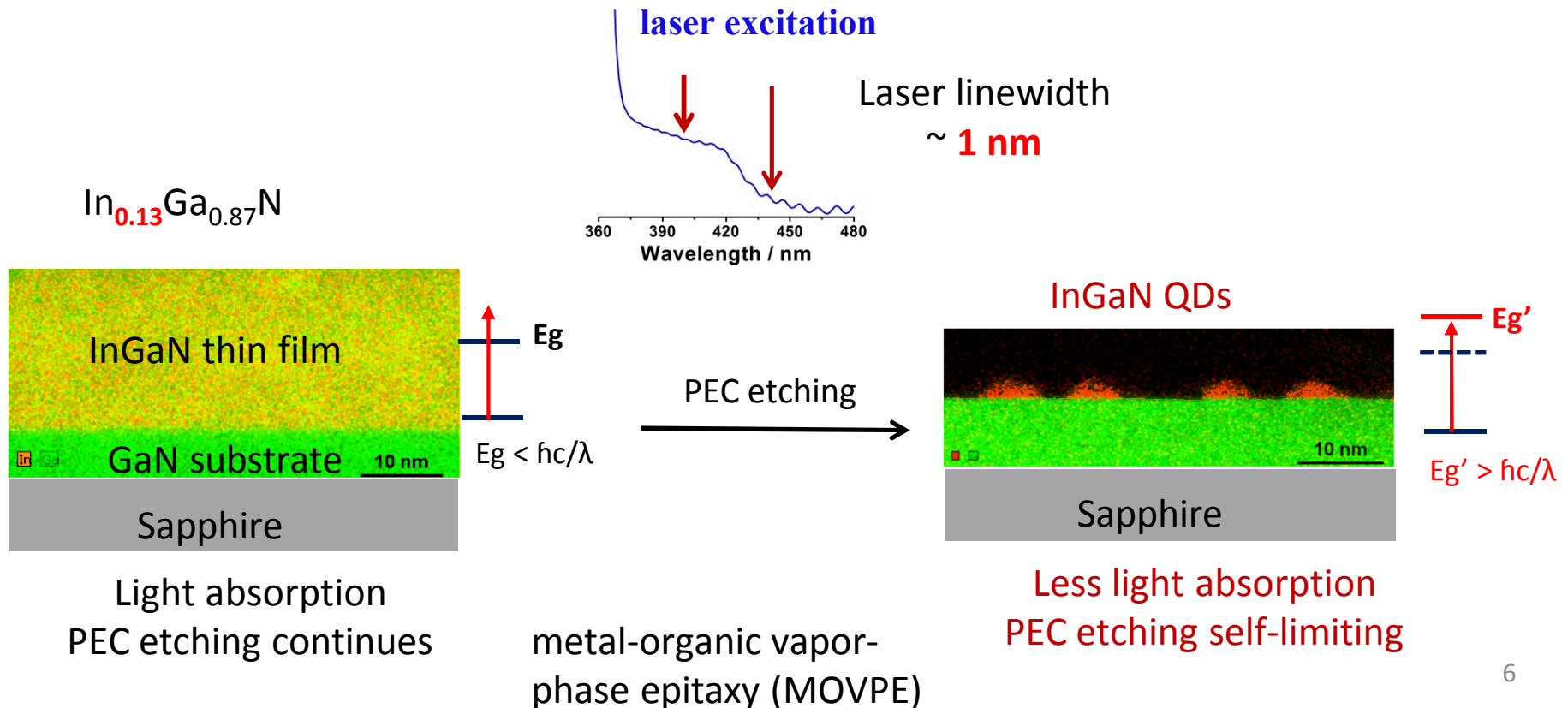
Cd/Se-ZnS core shell quantum dots

- Narrow size distribution
- Narrow PL peaks, ~50 nm above
- Passivation plays role

- ? Always dependent on organic/inorganic coatings
- ? No easy ways to integrate the dots into devices
- ? No colloidal chemistry for InGaN dots

# Contents

1. *Photoelectrochemistry*
2. *Quantum size controlled nanofabrication*
3. *PEC Quantum dots characterization: AFM, TEM, PL*
4. *Conclusions*

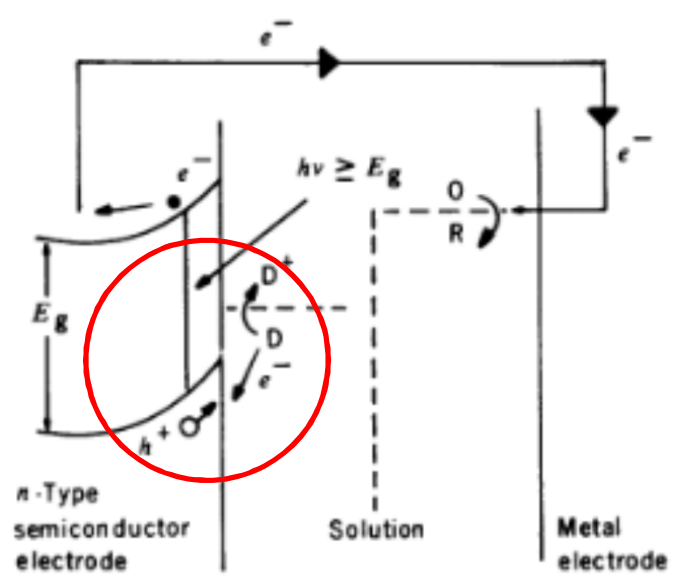




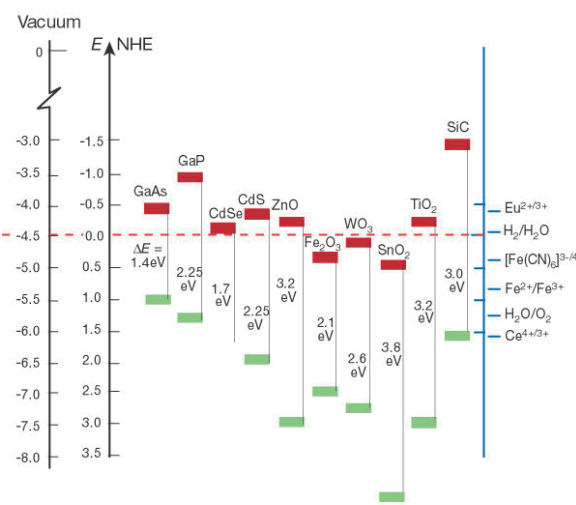
# Photoelectrochemistry: a wide range of applications

Chemical fuels ↔ Light ↔ Electricity

↓  
Semiconductor process



N-type semiconductor oxidation



11 January 1980, Volume 207, Number 4427

SCIENCE

## Photoelectrochemistry

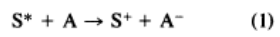
Allen J. Bard

The interconversion of different forms of energy has been of central importance in science and technology. Just as the practical application of heat engines, electric generators and motors, and storage batteries led to the development of the fields of thermodynamics and electrochemistry in the 19th and 20th centuries, so the problem of utilizing solar energy for the direct production of elec-

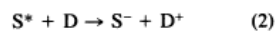
dry fuels, with overall field efficiencies of about 1 percent (1). The fabrication of artificial photosynthetic systems for the conversion of abundant materials (for example, H<sub>2</sub>O and CO<sub>2</sub>) to fuels (for example, H<sub>2</sub> and CH<sub>3</sub>OH), directly or by electrolysis or the production of electricity, is clearly an important goal (2, 3). Moreover, photochemical reactions could be employed to replace other ener-

**Summary.** The electron-hole pair formation that occurs at the interface between a semiconductor and a solution upon absorption of light leads to oxidation or reduction reactions of solution species. The principles of such photodriven processes are described as well as applications of semiconductors in electrochemical cells and as particulate systems for carrying out heterogeneous photocatalysis and photoelectrosynthesis.

one (Fig. 1A). The wavelength of light that causes such a transition is that with an energy equal to or greater than the difference in energies of the two orbitals,  $E_g$ . The result is an electron-hole ( $e^-h^+$ ) pair formed by this intramolecular pumping in species, S. This produces an excited state, denoted  $S^*$  (see Fig. 1A). If the  $e^-h^+$  pair can be separated so that the  $e^-$  flows to a suitable acceptor species, A,



or an electron from a suitable donor, D, fills  $h^+$

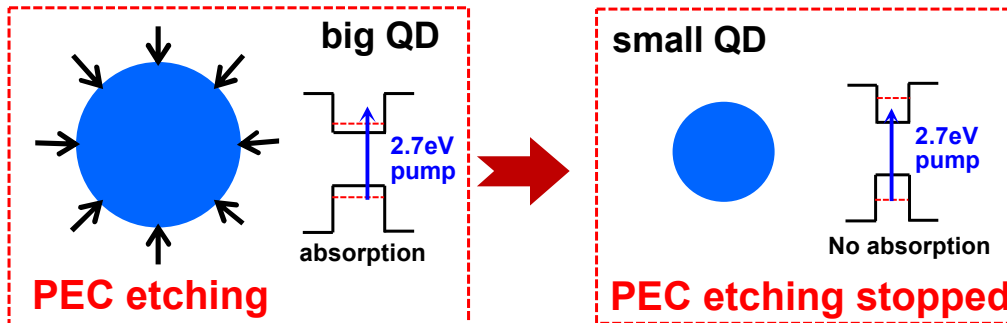


then the light energy has been stored, at least for a short time, as redox chemical energy. The reaction of  $S^+$  and  $A^-$  or  $S^-$  and  $D^+$  is spontaneous (or "downhill") and capable of liberating energy (that is, is exoergic). If  $e^-$  is pumped through a wire, it has been converted to an electrical current flow. However, excited states are very short-lived (typically lasting from nanoseconds to milliseconds in liquids) and the  $e^-h^+$  pairs frequently recombine very quickly with the captured light energy degraded to heat or, sometimes with the emission of a photon, as in

# Fabrication of InGaN QDs via PEC etching

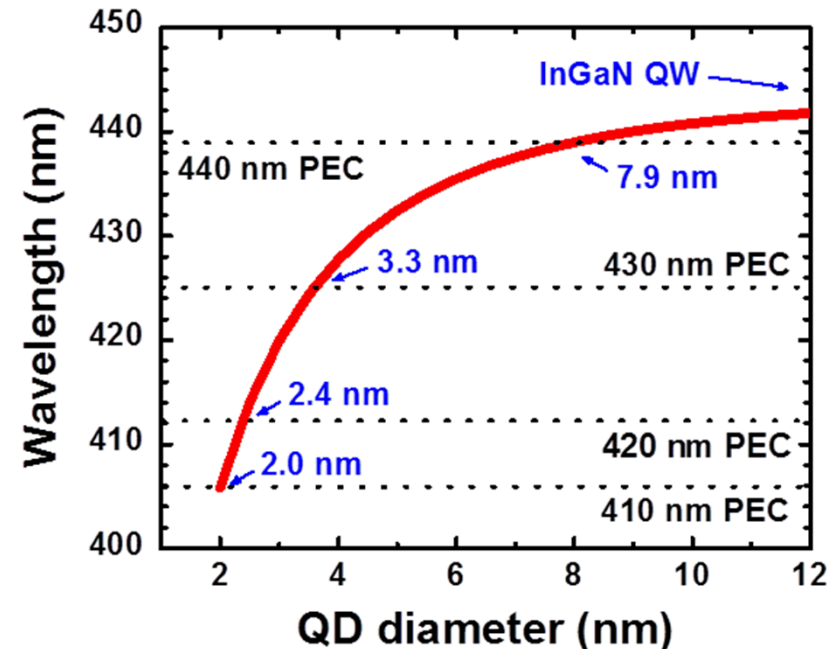
## Quantum Size Control: Use size quantization to control QD size

### Self-limiting PEC etch process:



- For QDs, band gap depends on size
- As etch proceeds,
  - QD size gets smaller, band gap goes up
  - Etch terminated for  $E_g > E_{\text{photon pump}}$
- **Self-terminating etch process**
- **QD size depends on PEC wavelength**
- **Extremely monodisperse QDs ?**

### Towards precision size control

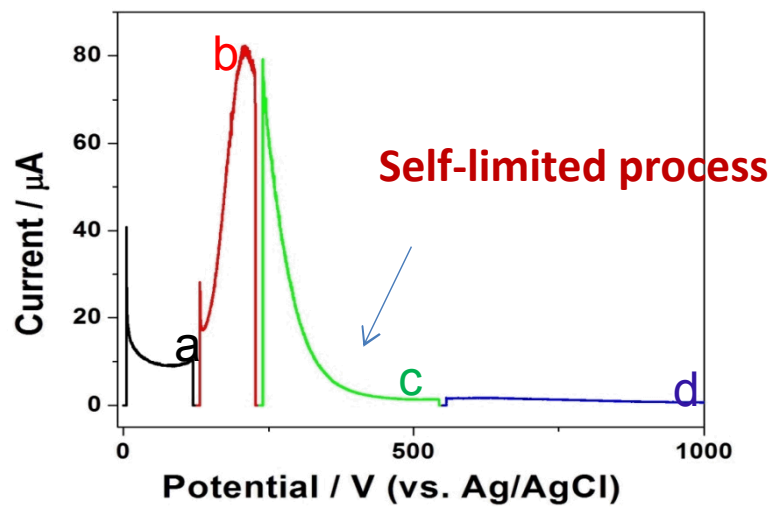
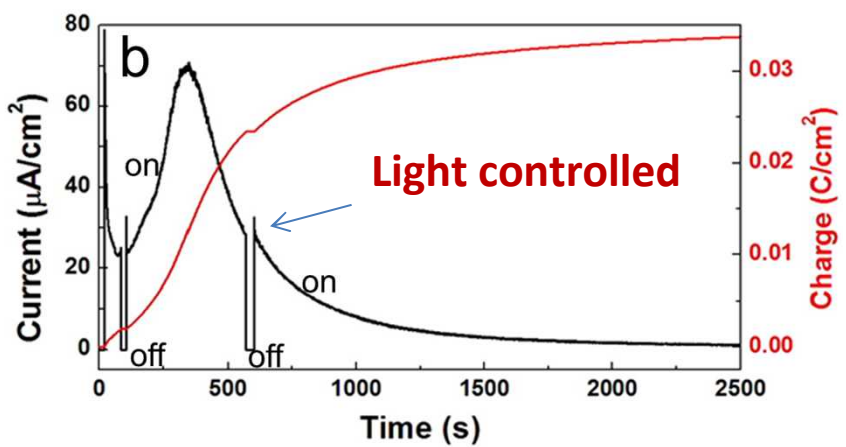
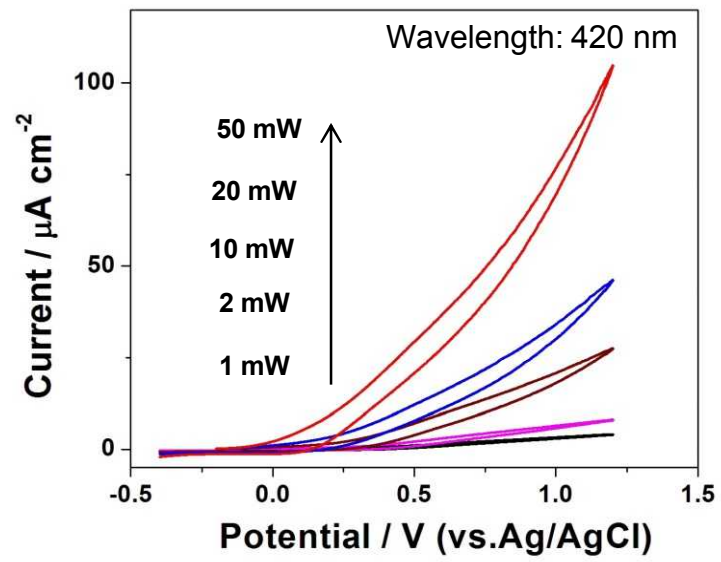
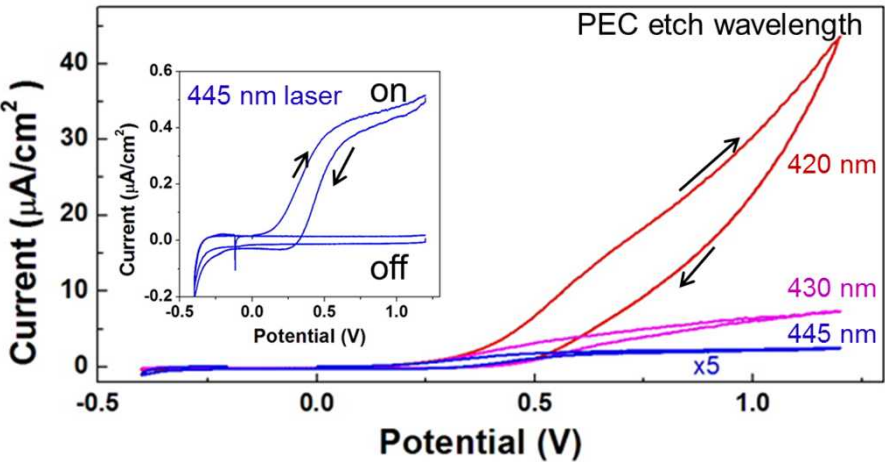


G. Pellegrini, et al., Journal of Applied Physics 97, 073706 (2005).



# Self-terminated photoelectrochemical etching

0.2 M  $\text{H}_2\text{SO}_4$



# MOCVD-grown InGaN QW samples

## Uncapped single InGaN QW



- Grown by MOCVD on sapphire substrates
  - 3 to 20 nm InGaN quantum well (QW)
- No InGaN underlayer is used in this sample
- Uncapped single QW sample (14% In):
  - Amenable to surface characterization of QDs
  - TEM, AFM characterization
  - Luminescence weaker than capped sample

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## Capped single InGaN QW



- Grown by MOCVD on sapphire substrates
  - 3 nm InGaN QW, 10 nm GaN cap
- InGaN underlayer (~2% In) used in this sample
- Capped single QW sample (14% In):
  - AFM is not useful for capped samples
  - Luminescence brighter than uncapped samples
- Etch is thought to proceed via pits, dislocations

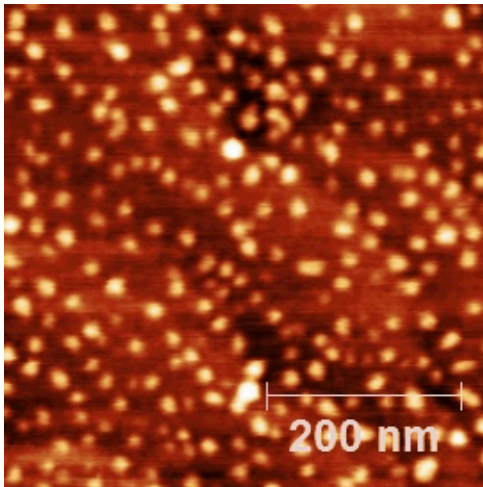
# Atomic Force Microscope (AFM) Measurements

## Uncapped InGaN QW

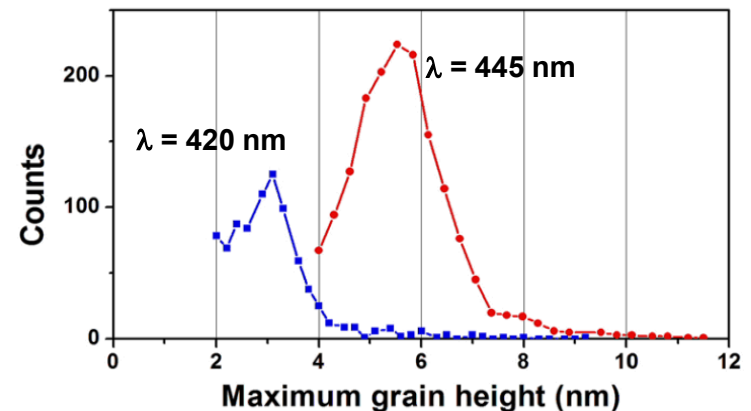
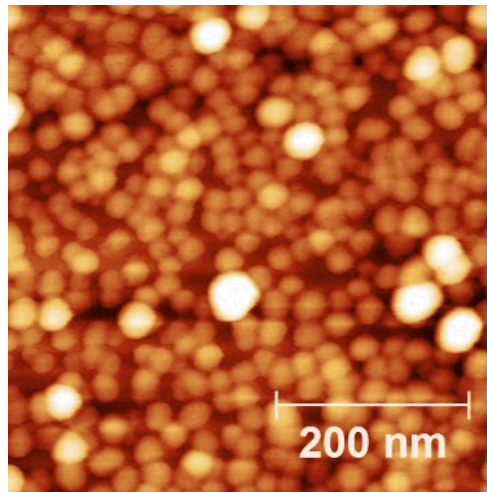


- Samples etched for two hours at 420 nm and 445 nm
  - Laser power density:  $\sim 3 \text{ mW/cm}^2$
- High dot density:  $10^{11}/\text{cm}^2$
- Some big dots (10-20 nm) remain: due to dislocations?
- QD size depends on PEC etch wavelength

## PEC etch $\rightarrow \lambda = 420 \text{ nm}$



## PEC etch $\rightarrow \lambda = 445 \text{ nm}$

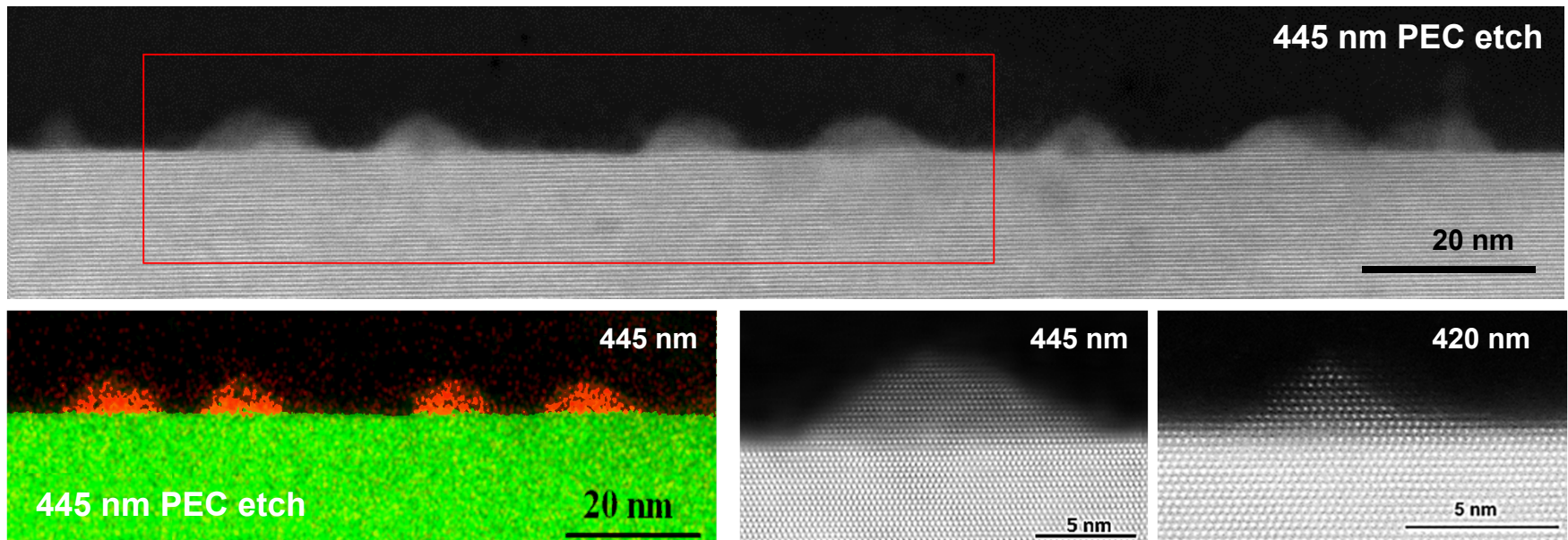


# Transmission Electron Microscope (TEM) Images

## Uncapped InGaN QW



- High-angle annular dark-field (HAADF) TEM images
- Samples etched at 420 nm and 445 nm
- Energy dispersive x-ray mapping
  - QDs on surface are InGaN
  - Red = indium, green=gallium
- InGaN QDs are epitaxial to the underlying GaN
- No underlayer, no cap → PL is not very bright



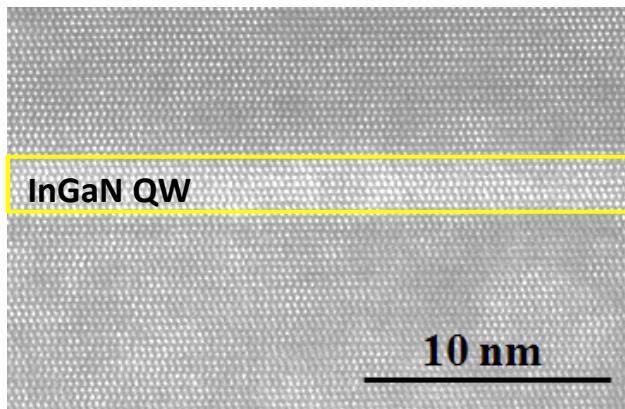
# Transmission Electron Microscope Images

## Capped InGaN QW

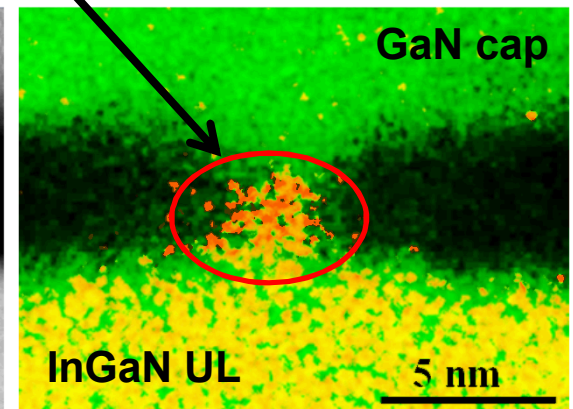
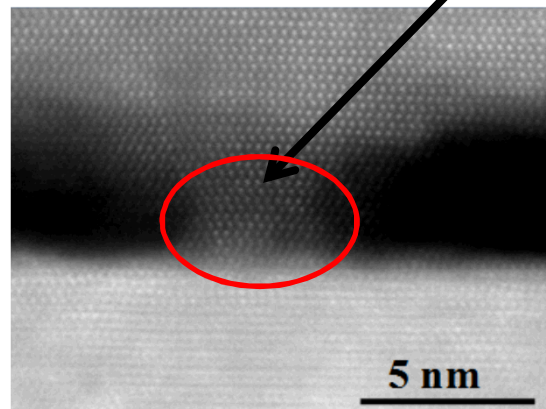


- High-angle annular dark-field (HAADF) TEM images
- Sample etched at 420 nm
- EDX mapping shows that dots are InGaN
- InGaN QDs are epitaxial to the underlying GaN
- 2% InGaN underlayer + GaN cap → PL is much brighter
- GaN cap provides partial passivation

Before etch

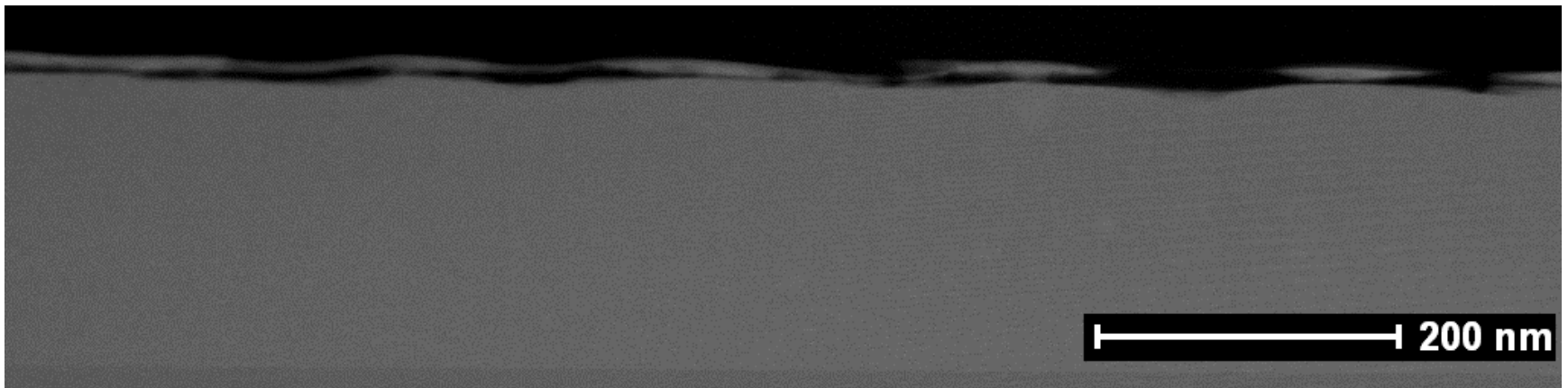
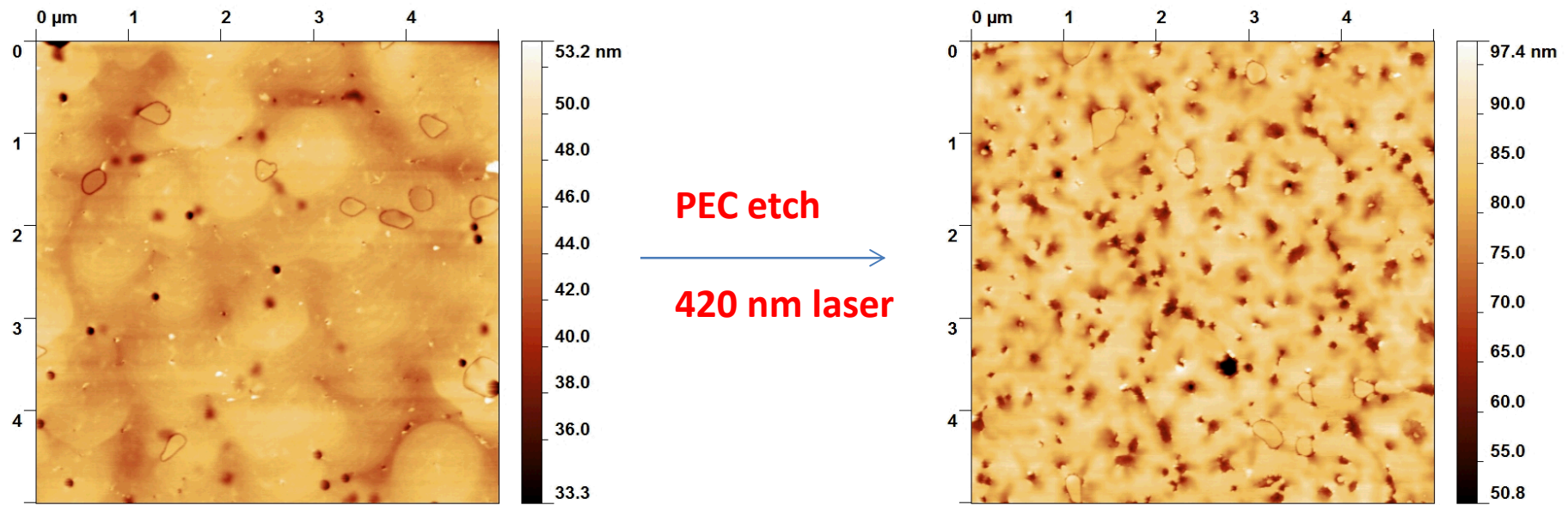


InGaN QD





# PEC etch of capped InGaN quantum wells





# Photoluminescence from fabricated InGaN QDs

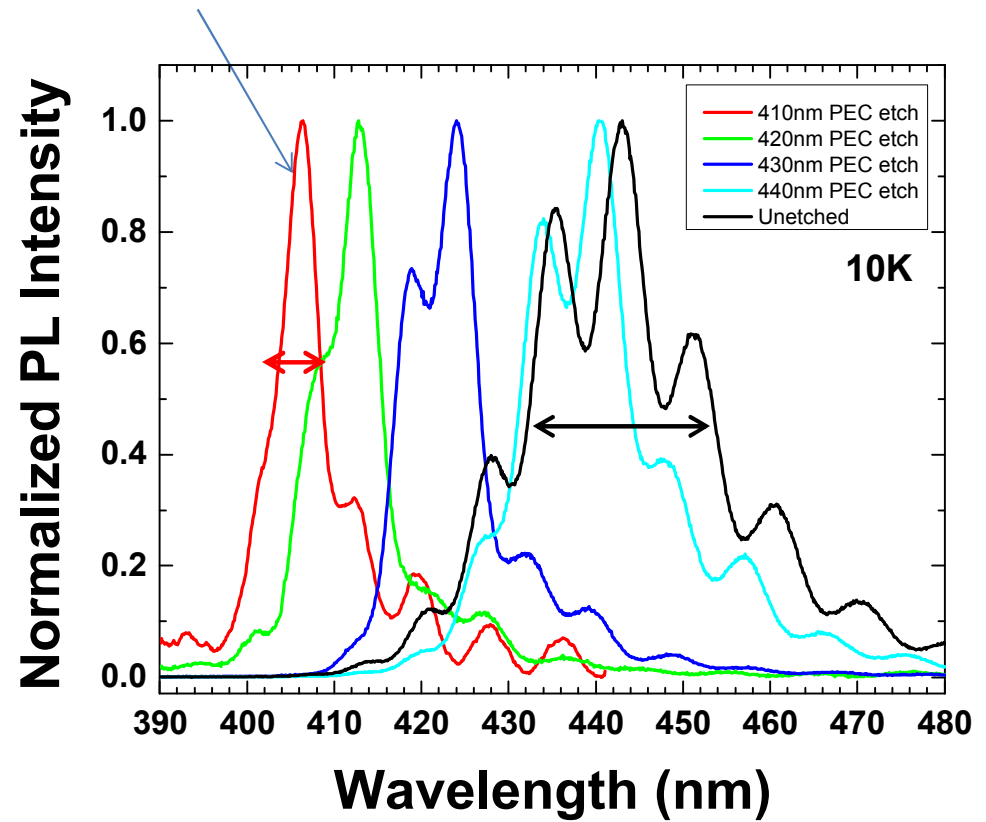
## Capped InGaN QW

GaN cap
InGaN QW
InGaN underlayer
n-GaN
Sapphire

## Photoluminescence (PL) data:

- 375 nm pump (ps pulsed)
- 10K PL data
- PL wavelength determined by PEC etch wavelength
- PL linewidth: 24 nm  $\rightarrow$  6 nm
- **Quantum size-controlled PEC etching works!**

As narrow as **6 nm** FWHM is consistent with a narrowing of the QD size distribution

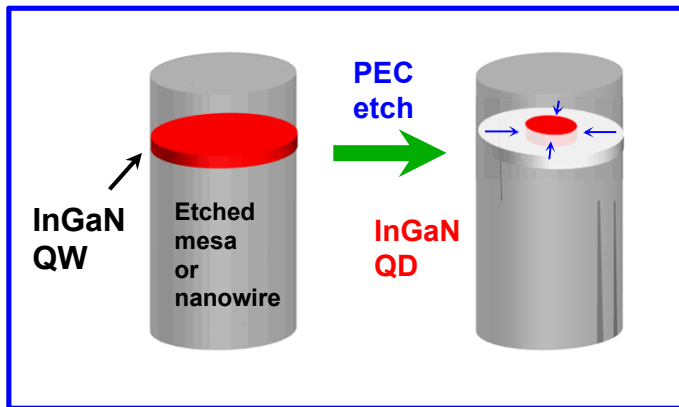


# Emission from single InGaN QDs

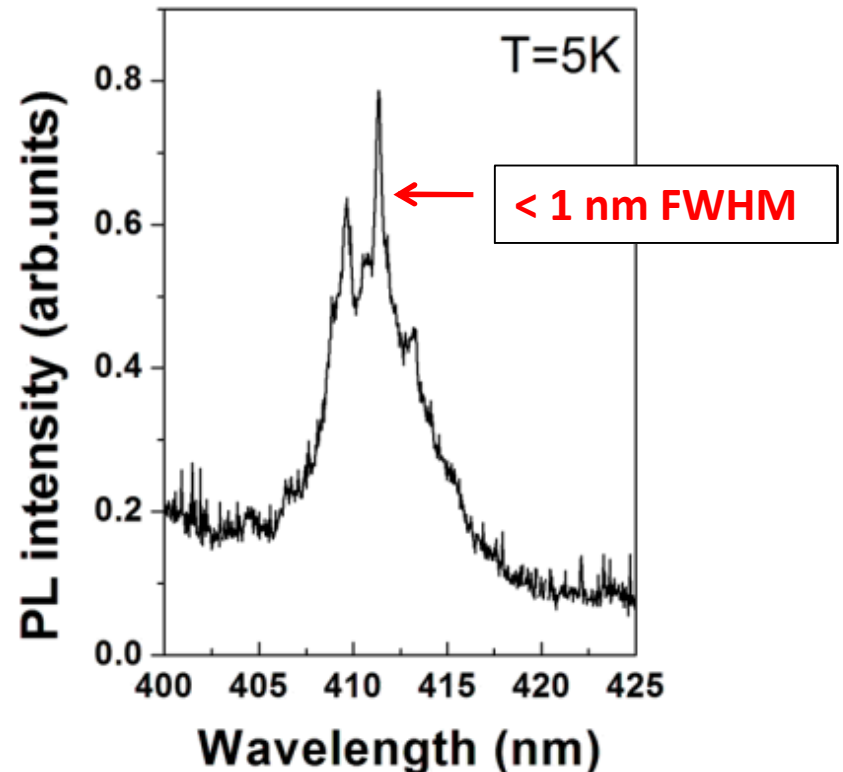
## Capped InGaN QW

GaN cap
InGaN QW
InGaN underlayer
n-GaN
Sapphire

- Posts (150 – 200 nm) patterned with e-beam lithography
- Narrow PL emission (<1 nm FWHM) observed
- Fabricate InGaN QDs at deterministic locations
- InGaN QD single photon source

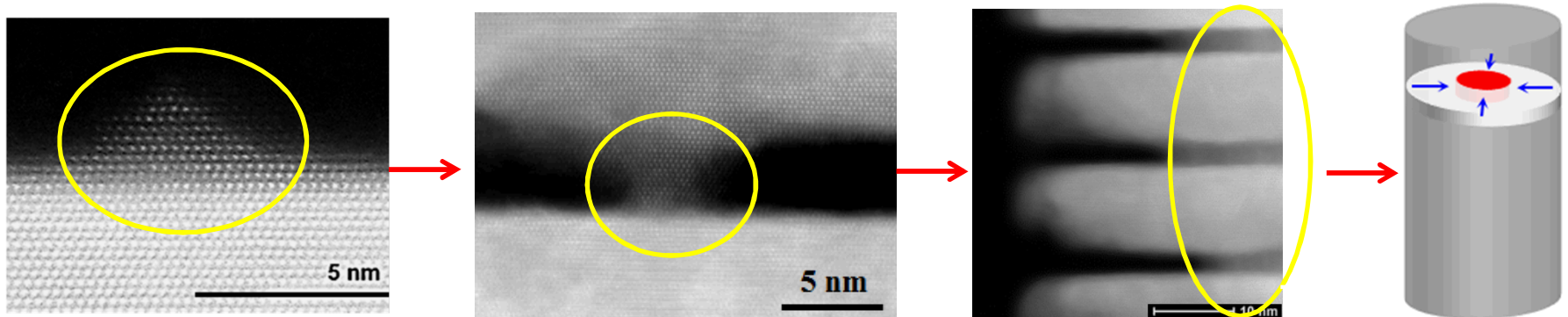


**Deterministic locations**



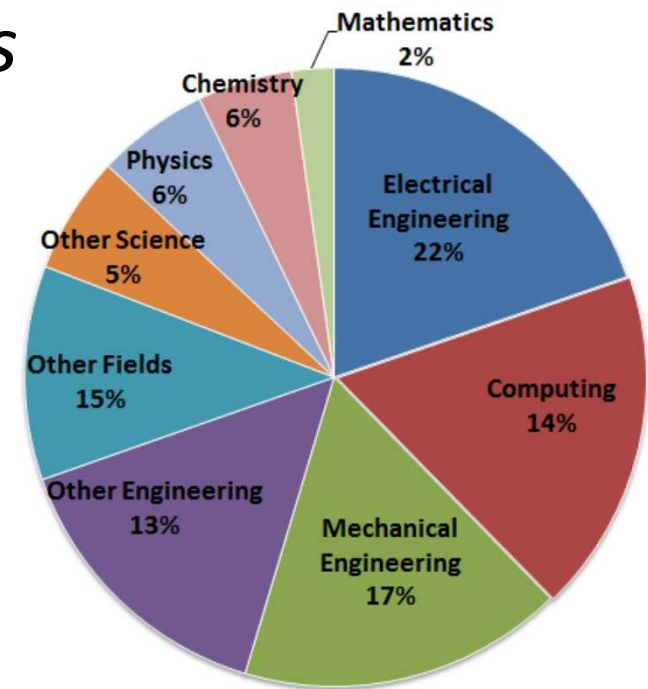
# Summary/Conclusions

- Demonstrated fabricated InGaN QDs using PEC etching
  - AFM data indicates  **$10^{11}$**  QDs per  $\text{cm}^2$
  - TEM EDX mapping shows we have **epitaxial** InGaN QDs
- Quantum size-controlled etching of InGaN QDs
  - **QD size and emission  $\lambda$  determined by PEC wavelength**
- PL linewidth reduced from 35 nm to less than **6 nm**
  - Shows an improved QD size distribution
- Demonstrated emission from single InGaN QDs
  - Working towards **deterministic placement** of InGaN QDs



# About Sandia National Laboratories

- ✓ On-site workforce: ~12,000
- ✓ FY13 budget: \$2.3 billion



*Albuquerque, New Mexico*



*Livermore, California*

